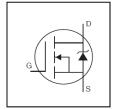


AUIRFR3710Z

HEXFET® Power MOSFET

Features

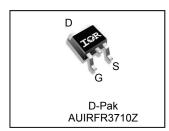
- Advanced Process Technology
- Ultra Low On-Resistance
- 175°C Operating Temperature
- Fast Switching
- · Repetitive Avalanche Allowed up to Timax
- Lead-Free, RoHS Compliant
- Automotive Qualified *



V _{DSS}	100V
R _{DS(on)} max.	18mΩ
D (Silicon Limited)	56A
D (Package Limited)	42A

Description

Specifically designed for Automotive applications, this HEXFET® Power MOSFET utilizes the latest processing techniques to achieve extremely low on-resistance per silicon area. Additional features of this design are a 175°C junction operating temperature, fast switching speed and improved repetitive avalanche rating. These features combine to make this design an extremely efficient and reliable device for use in Automotive applications and a wide variety of other applications.



G	D	S
Gate	Drain	Source

Base next number Backene Time		Standard Pack		Orderable Part Number		
Base part number	Package Type	Form Quantit		Form Quar		Orderable Part Number
AUIRFR3710Z	D. Dok	Tube	75	AUIRFR3710Z		
AUIRFR3/10Z	D-Pak	Tape and Reel Left	3000	AUIRFR3710ZTRL		

Absolute Maximum Ratings

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only; and functional operation of the device at these or any other condition beyond those indicated in the specifications is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability. The thermal resistance and power dissipation ratings are measured under board mounted and still air conditions. Ambient temperature (TA) is 25°C, unless otherwise specified.

Symbol	Parameter	Max.	Units
I _D @ T _C = 25°C	Continuous Drain Current, V _{GS} @ 10V (Silicon Limited)	56	
I _D @ T _C = 100°C	Continuous Drain Current, V _{GS} @ 10V (Silicon Limited)	39	A
I _D @ T _C = 25°C	Continuous Drain Current, V _{GS} @ 10V (Package Limited)	42	
I _{DM}	Pulsed Drain Current ①	220	1
P _D @T _C = 25°C	Maximum Power Dissipation	140	W
	Linear Derating Factor	0.95	W/°C
V_{GS}	Gate-to-Source Voltage	± 20	V
E _{AS}	Single Pulse Avalanche Energy (Thermally Limited) ②	150	ma I
E _{AS} (Tested)	Single Pulse Avalanche Energy Tested Value ®	200	- mJ
I _{AR}	Avalanche Current ①	See Fig.15,16, 12a, 12b	Α
E _{AR}	Repetitive Avalanche Energy ®		mJ
T_J	Operating Junction and	-55 to + 175	
T _{STG}	Storage Temperature Range		°C
	Soldering Temperature, for 10 seconds (1.6mm from case)	300	

Thermal Resistance

Symbol Parameter		Тур.	Max.	Units
$R_{\theta JC}$	Junction-to-Case ®		1.05	
$R_{\theta JA}$	Junction-to-Ambient (PCB Mount) ⑦		50	°C/W
$R_{\theta JA}$	Junction-to-Ambient		110	

HEXFET® is a registered trademark of Infineon.

^{*}Qualification standards can be found at www.infineon.com



Static @ T_J = 25°C (unless otherwise specified)

	Parameter	Min.	Тур.	Max.	Units	Conditions
$V_{(BR)DSS}$	Drain-to-Source Breakdown Voltage	100			V	$V_{GS} = 0V, I_D = 250\mu A$
$\Delta V_{(BR)DSS}/\Delta T_{J}$	Breakdown Voltage Temp. Coefficient		0.088		V/°C	Reference to 25°C, I _D = 1mA
R _{DS(on)}	Static Drain-to-Source On-Resistance		15	18	mΩ	V _{GS} = 10V, I _D = 33A ③
$V_{GS(th)}$	Gate Threshold Voltage	2.0		4.0	٧	$V_{DS} = V_{GS}$, $I_D = 250\mu A$
gfs	Forward Trans conductance	39			S	$V_{DS} = 25V, I_{D} = 33A$ ③
	Drain to Source Leakage Current			20		$V_{DS} = 100V, V_{GS} = 0V$
IDSS	Drain-to-Source Leakage Current			250	μA	$V_{DS} = 100V, V_{GS} = 0V, T_{J} = 125$ °C
	Gate-to-Source Forward Leakage			200	n ^	V _{GS} = 20V
I _{GSS}	Gate-to-Source Reverse Leakage			-200	nA	$V_{GS} = -20V$

Dynamic Electrical Characteristics @ T_J = 25°C (unless otherwise specified)

Q_g	Total Gate Charge	 69	100		I _D = 33A
Q_{gs}	Gate-to-Source Charge	 15		nC	$V_{DS} = 80V$
$\overline{Q_{gd}}$	Gate-to-Drain Charge	 25			V _{GS} = 10V③
$t_{d(on)}$	Turn-On Delay Time	 14			$V_{DD} = 50V$
t _r	Rise Time	 43			$I_D = 33A$
$t_{d(off)}$	Turn-Off Delay Time	 53		ns	$R_G = 6.8\Omega$
t _f	Fall Time	 42			V _{GS} = 10V③
L _D	Internal Drain Inductance	 4.5			Between lead, 6mm (0.25in.)
L _S	Internal Source Inductance	 7.5			from package and center of die contact
C _{iss}	Input Capacitance	 2930			$V_{GS} = 0V$
Coss	Output Capacitance	 290			$V_{DS} = 25V$
C _{rss}	Reverse Transfer Capacitance	 180		nΕ	f = 1.0MHz
C _{oss}	Output Capacitance	 1200		pF	$V_{GS} = 0V$, $V_{DS} = 1.0V$ $f = 1.0MHz$
C _{oss}	Output Capacitance	 180			$V_{GS} = 0V, V_{DS} = 80V f = 1.0MHz$
Coss eff.	Effective Output Capacitance	 430			$V_{GS} = 0V, V_{DS} = 0V \text{ to } 80V $

Diode Characteristics

	Parameter	Min.	Тур.	Max.	Units	Conditions
I _S	Continuous Source Current (Body Diode)			56		MOSFET symbol showing the
I _{SM}	Pulsed Source Current (Body Diode) ①			220		integral reverse p-n junction diode.
V_{SD}	Diode Forward Voltage			1.3	٧	$T_J = 25^{\circ}C, I_S = 33A, V_{GS} = 0V$ ③
t _{rr}	Reverse Recovery Time		35	53	ns	$T_J = 25^{\circ}C$, $I_F = 33A$, $V_{DD} = 50V$
Q_{rr}	Reverse Recovery Charge		41	62	nC	di/dt = 100A/µs ③
t _{on}	Forward Turn-On Time	Intrinsi	Intrinsic turn-on time is negligible (turn-on is dominated by L _S +L _D)			

Notes:

- ① Repetitive rating; pulse width limited by max. junction temperature. (See fig. 11)

- \oplus C_{oss} eff. is a fixed capacitance that gives the same charging time as C_{oss} while V_{DS} is rising from 0 to 80% V_{DSS}
- © Limited by T_{Jmax}, see Fig.12a, 12b, 15, 16 for typical repetitive avalanche performance.
- ⑥ This value determined from sample failure population, starting $T_J = 25$ °C, L = 0.28mH, R_G = 25Ω, I_{AS} = 33A, V_{GS} =10V.
- When mounted on 1" square PCB (FR-4 or G-10 Material). For recommended footprint and soldering techniques refer to application note #AN-994
- ® R_{θ} is measured at T_{J} approximately 90°C.



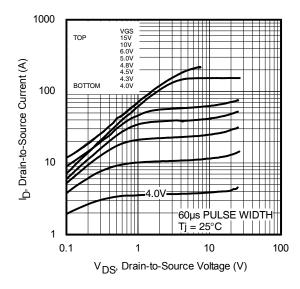


Fig. 1 Typical Output Characteristics

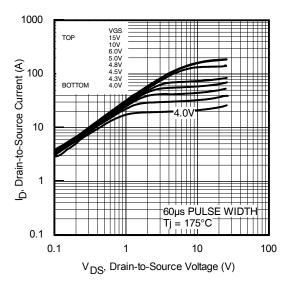


Fig. 2 Typical Output Characteristics

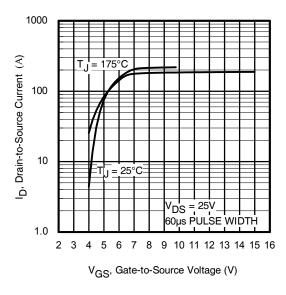


Fig. 3 Typical Transfer Characteristics

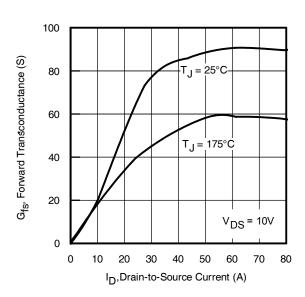


Fig. 4 Typical Forward Trans conductance Vs. Drain Current



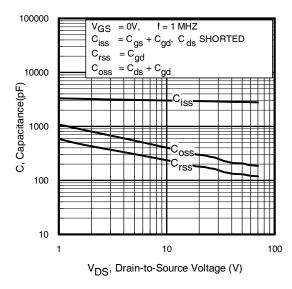


Fig 5. Typical Capacitance vs. Drain-to-Source Voltage

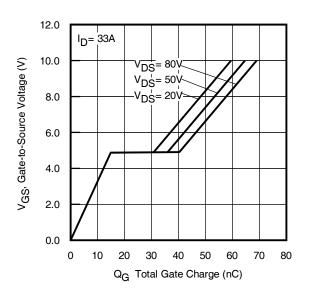


Fig 6. Typical Gate Charge vs. Gate-to-Source Voltage

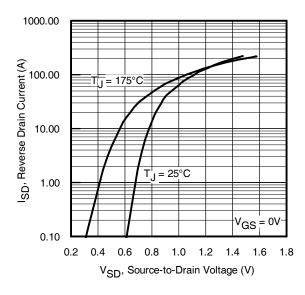


Fig. 7 Typical Source-to-Drain Diode Forward Voltage

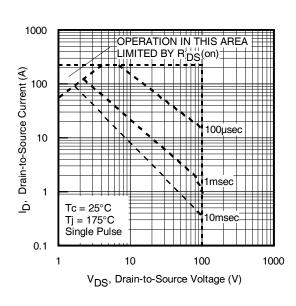
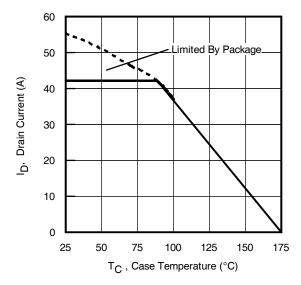


Fig 8. Maximum Safe Operating Area





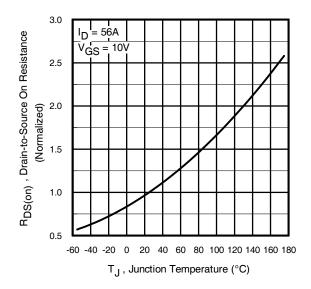


Fig 9. Maximum Drain Current Vs. Case Temperature

Fig 10. Normalized On-Resistance Vs. Temperature

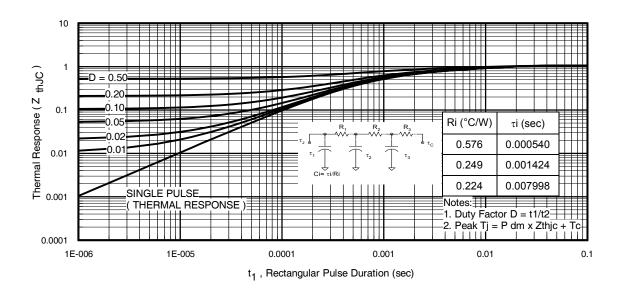


Fig 11. Maximum Effective Transient Thermal Impedance, Junction-to-Case



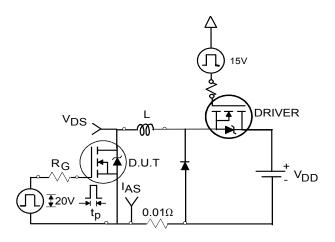


Fig 12a. Unclamped Inductive Test Circuit

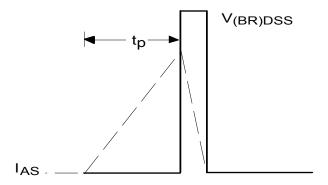


Fig 12b. Unclamped Inductive Waveforms

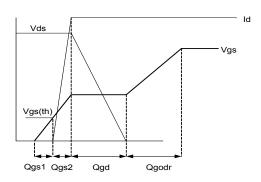


Fig 13a. Gate Charge Waveform

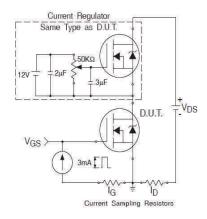


Fig 13b. Gate Charge Test Circuit

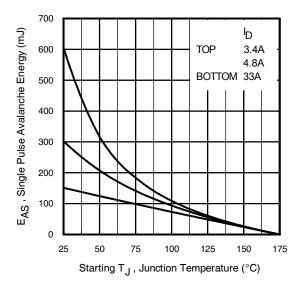


Fig 12c. Maximum Avalanche Energy vs. Drain Current

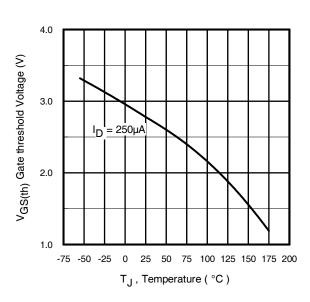


Fig 14. Threshold Voltage Vs. Temperature



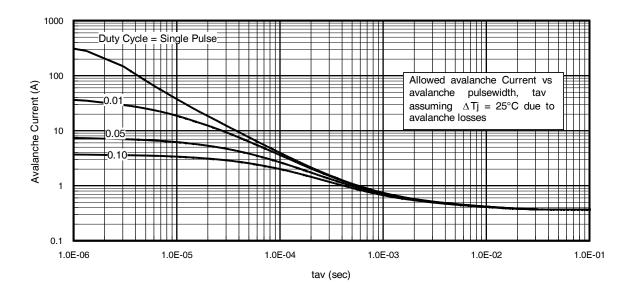


Fig 15. Typical Avalanche Current Vs. Pulse width

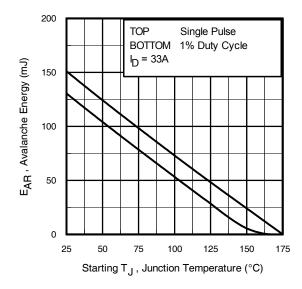


Fig 16. Maximum Avalanche Energy Vs. Temperature

Notes on Repetitive Avalanche Curves, Figures 15, 16:

(For further info, see AN-1005 at www.infineon.com)

- Avalanche failures assumption:
 Purely a thermal phenomenon and failure occurs at a temperature far in excess of T_{imax}. This is validated for every part type.
- 2. Safe operation in Avalanche is allowed as long as T_{jmax} is not exceeded.
- 3. Equation below based on circuit and waveforms shown in Figures 12a, 12b.
- 4. PD (ave) = Average power dissipation per single avalanche pulse.
- BV = Rated breakdown voltage (1.3 factor accounts for voltage increase during avalanche).
- 6. Iav = Allowable avalanche current.
- 7. ΔT = Allowable rise in junction temperature, not to exceed T_{jmax} (assumed as 25°C in Figure 15, 16).

tav = Average time in avalanche.

D = Duty cycle in avalanche = tav ·f

ZthJC(D, tav) = Transient thermal resistance, see Figures 13)

$$\begin{split} P_{D \; (ave)} &= 1/2 \; (\; 1.3 \cdot BV \cdot I_{av}) = \Delta T / \; Z_{thJC} \\ I_{av} &= 2\Delta T / \; [1.3 \cdot BV \cdot Z_{th}] \\ E_{AS \; (AR)} &= P_{D \; (ave)} \cdot t_{av} \end{split}$$



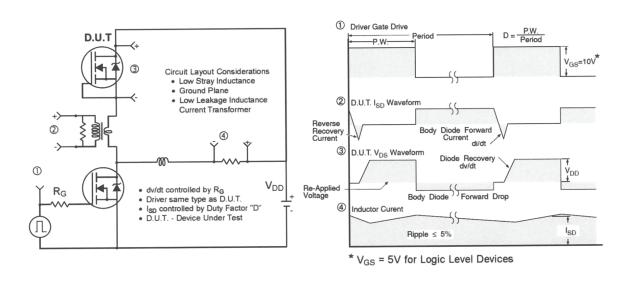


Fig 17. Peak Diode Recovery dv/dt Test Circuit for N-Channel HEXFET® Power MOSFETs

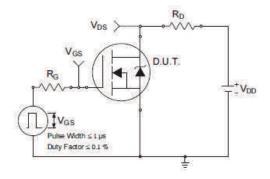


Fig 18a. Switching Time Test Circuit

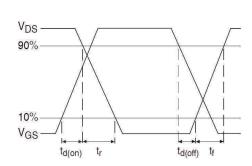
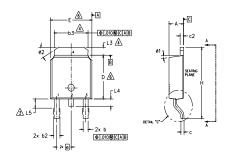


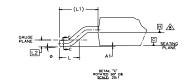
Fig 18b. Switching Time Waveforms

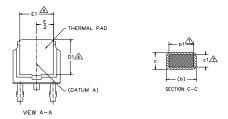


D-Pak (TO-252AA) Package Outline (Dimensions are shown in millimeters (inches))









NOTES:

- 1.- DIMENSIONING AND TOLERANCING PER ASME Y14.5M-1994
- 2.- DIMENSION ARE SHOWN IN INCHES [MILLIMETERS].
- 3- LEAD DIMENSION UNCONTROLLED IN L5.
- A- DIMENSION D1, E1, L3 & b3 ESTABLISH A MINIMUM MOUNTING SURFACE FOR THERMAL PAD.
- 5.— SECTION C-C DIMENSIONS APPLY TO THE FLAT SECTION OF THE LEAD BETWEEN .005 AND 0.10 [0.13 AND 0.25] FROM THE LEAD TIP.
- Limited Dimension D & E DO NOT INCLUDE MOLD FLASH. MOLD FLASH SHALL NOT EXCEED .005 [0.13] PER SIDE. THESE DIMENSIONS ARE MEASURED AT THE OUTMOST EXTREMES OF THE PLASTIC BODY.
- ⚠- DIMENSION b1 & c1 APPLIED TO BASE METAL ONLY.
- ♠ DATUM A & B TO BE DETERMINED AT DATUM PLANE H.
- 9.- OUTLINE CONFORMS TO JEDEC OUTLINE TO-252AA.

S Y M	DIMENSIONS					
B	MILLIM	ETERS	INC	HES	O T E S	
L	MIN.	MAX.	MIN.	MAX.	S	
Α	2.18	2.39	.086	.094		
A1	-	0.13	-	.005		
b	0.64	0.89	.025	.035		
ь1	0.65	0.79	.025	.031	7	
b2	0.76	1.14	.030	.045		
b3	4.95	5.46	.195	.215	4	
С	0.46	0.61	.018	.024		
c1	0.41	0.56	.016	.022	7	
c2	0.46	0.89	.018	.035		
D	5.97	6.22	.235	.245	6	
D1	5.21	-	.205	-	4	
Ε	6.35	6.73	.250	.265	6	
E1	4.32	-	.170	-	4	
е	2.29	BSC .090 BSC				
Н	9.40	10.41	.370	.410		
L	1.40	1.78	.055	.070		
L1	2.74	BSC	.108	REF.		
L2	0.51	BSC	.020	BSC		
L3	0.89	1.27	.035	.050	4	
L4	-	1.02	-	.040		
L5	1.14	1.52	.045	.060	3	
ø	0,	10*	0,	10°		
ø1	0,	15*	0,	15*		
ø2	25*	35°	25*	35°		

LEAD ASSIGNMENTS

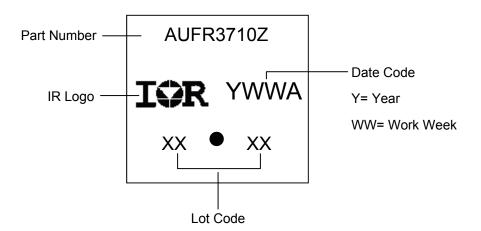
HEXFET

- 1.- GATE
- 2.- DRAIN
- 3.- SOURCE
- 4.- DRAIN

IGBT & CoPAK

- 1.- GATE
- 2.- COLLECTOR
- 3.- EMITTER
- 4.- COLLECTOR

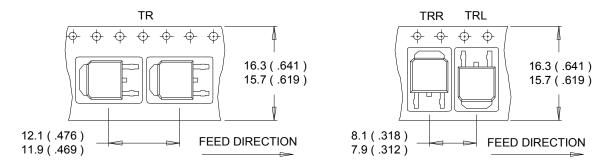
D-Pak (TO-252AA) Part Marking Information



Note: For the most current drawing please refer to IR website at http://www.irf.com/package/

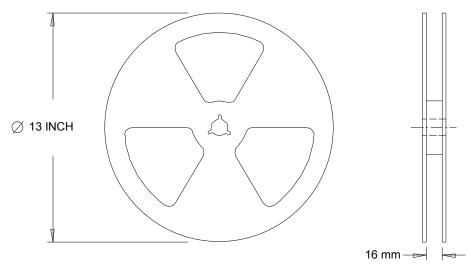


D-Pak (TO-252AA) Tape & Reel Information (Dimensions are shown in millimeters (inches))



NOTES:

- 1. CONTROLLING DIMENSION: MILLIMETER.
- 2. ALL DIMENSIONS ARE SHOWN IN MILLIMETERS (INCHES).
- 3. OUTLINE CONFORMS TO EIA-481 & EIA-541.



NOTES:

1. OUTLINE CONFORMS TO EIA-481.

Note: For the most current drawing please refer to IR website at http://www.irf.com/package/



Qualification Information

		Automotive (per AEC-Q101)				
Qualification Level Comments: This part number(s) passed Automotive qualification. Industrial and Consumer qualification level is granted by extension of t Automotive level.						
Moisture	Sensitivity Level	D-Pak MSL1				
	Machine Madel	Class M4 [†]				
	Machine Model	AEC-Q101-002				
FOR	Livers on Dady Madal		Class H1C [†]			
ESD	Human Body Model	AEC-Q101-001				
	Observed Basis a Madal	Class C3 [†]				
Charged Device Model		AEC-Q101-005				
RoHS Con	npliant	Yes				

[†] Highest passing voltage.

Revision History

Date	Comments			
11/23/2015	Updated datasheet with corporate template			
11/23/2013	Corrected ordering table on page 1.			

Published by Infineon Technologies AG 81726 München, Germany © Infineon Technologies AG 2015 All Rights Reserved.

IMPORTANT NOTICE

The information given in this document shall in <u>no event</u> be regarded as a guarantee of conditions or characteristics ("Beschaffenheitsgarantie"). With respect to any examples, hints or any typical values stated herein and/or any information regarding the application of the product, Infineon Technologies hereby disclaims any and all warranties and liabilities of any kind, including without limitation warranties of non-infringement of intellectual property rights of any third party.

In addition, any information given in this document is subject to customer's compliance with its obligations stated in this document and any applicable legal requirements, norms and standards concerning customer's products and any use of the product of Infineon Technologies in customer's applications.

The data contained in this document is exclusively intended for technically trained staff. It is the responsibility of customer's technical departments to evaluate the suitability of the product for the intended application and the completeness of the product information given in this document with respect to such application.

For further information on the product, technology, delivery terms and conditions and prices please contact your nearest Infineon Technologies office (www.infineon.com).

WARNINGS

Due to technical requirements products may contain dangerous substances. For information on the types in question please contact your nearest Infineon Technologies office.

Except as otherwise explicitly approved by Infineon Technologies in a written document signed by authorized representatives of Infineon Technologies, Infineon Technologies' products may <u>not</u> be used in any applications where a failure of the product or any consequences of the use thereof can reasonably be expected to result in personal injury.

单击下面可查看定价,库存,交付和生命周期等信息

>>Infineon Technologies(英飞凌)